Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/779,779	NIIYA, HIROTAKA	
Examiner	Art Unit	
W. Patty Chen	2871	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	DATE	EXMR
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